

MOS FIELD EFFECT TRANSISTOR

2SK3481

SWITCHING N-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

The 2SK3481 is N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

• Super low on-state resistance:

 $R_{DS(on)1}$ = 46 $m\Omega$ MAX. (Vgs = 10 V, Ip = 15 A)

 $R_{DS(on)2} = 53 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.5 \text{ V, Id} = 15 \text{ A)}$

- Low Ciss: Ciss = 2300 pF TYP.
- Built-in gate protection diode

ORDERING INFORMATION

PART NUMBER	PACKAGE
2SK3481	TO-220AB
2SK3481-S	TO-262
2SK3481-ZJ	TO-263
2SK3481-Z	TO-220SMD ^{Note}

Note TO-220SMD package is produced only in Japan.

(TO-220AB)

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage	VDSS	100	V
Gate to Source Voltage	$V_{\text{GSS(AC)}}$	±20	V
Drain Current (DC)	$I_{D(DC)}$	±30	Α
Drain Current (pulse) Note1	D(pulse)	±120	Α
Total Power Dissipation (Tc = 25°C)	Рт	56	W
Total Power Dissipation (T _A = 25°C)	Рт	1.5	W
Channel Temperature	Tch	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C
Single Avalanche Current Note2	las	T.B.D. Note3	Α
Single Avalanche Energy Note2	Eas	T.B.D. Note3	mJ

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1 %

2. Starting Tch = 25 °C, RG = 25 Ω , VGS = 20 V \rightarrow 0 V

3. T.B.D.: To be determined



(TO-262)



(TO-263, TO-220SMD)



THERMAL RESISTANCE

Channel to Case	$R_{th(ch-C)}$	2.23	°C/W	
Channel to Ambient	Rth(ch-A)	83.3	°C/W	

The information contained in this document is being issued in advance of the production cycle for the device. The parameters for the device may change before final production or NEC Corporation, at its own discretion, may withdraw the device prior to its production.

Not all devices/types available in every country. Please check with local NEC representative for availability and additional information.

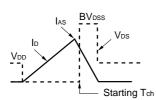


ELECTRICAL CHARACTERISTICS (TA = 25 °C)

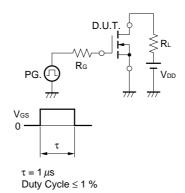
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CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	V _G S = 10 V, I _D = 15 A		36	46	mΩ
	RDS(on)2	Vgs = 4.5 V, ID = 15 A		39	53	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	Vps = 10 V, Ip = 15 A	16	32		S
Drain Leakage Current	IDSS	V _{DS} = 100 V, V _{GS} = 0 V			10	μΑ
Gate to Source Leakage Current	Igss	VGS = ±20 V, VDS = 0 V			±10	μΑ
Input Capacitance	Ciss	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		2300		pF
Output Capacitance	Coss			230		pF
Reverse Transfer Capacitance	Crss			120		рF
Turn-on Delay Time	t d(on)	ID = 15 A, VGS(on) = 10 V, VDD = 50 V,		17		ns
Rise Time	tr	$R_G = 1 \Omega$		10		ns
Turn-off Delay Time	t d(off)			55		ns
Fall Time	t _f			9.0		ns
Total Gate Charge	QG	ID = 30 A , VDD = 80 V, VGS = 10 V		42		nC
Gate to Source Charge	Qgs			7.0		nC
Gate to Drain Charge	QGD			12		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 30 A, VGS = 0 V		1.0		V
Reverse Recovery Time	trr	IF = 30 A, VGS = 0 V,		88		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		170		nC

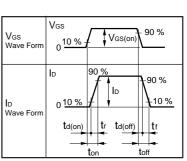
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{RG} = 25 \ \Omega \\ \text{PG.} \\ \text{VGS} = 20 \rightarrow 0 \ \text{V} \\ \text{m} \end{array} \begin{array}{c} \text{D.U.T.} \\ \text{RG} = 25 \ \Omega \\ \text{M} \end{array}$

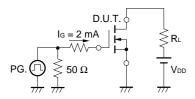


TEST CIRCUIT 2 SWITCHING TIME





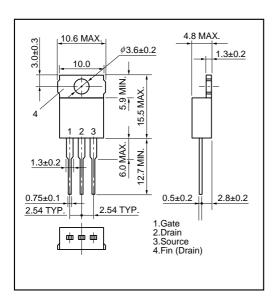
TEST CIRCUIT 3 GATE CHARGE



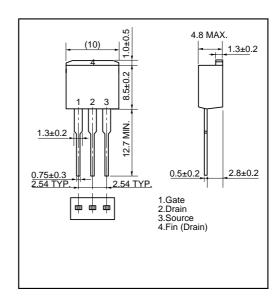


PACKAGE DRAWINGS (Unit: mm)

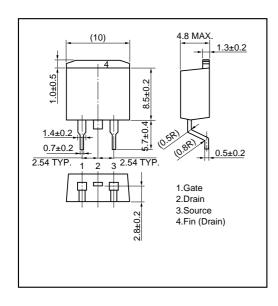
1) TO-220AB(MP-25)



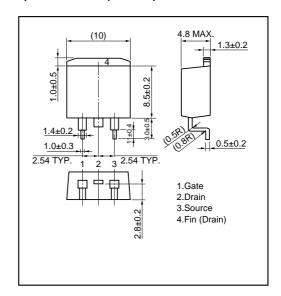
2) TO-262(MP-25 Fin Cut)



3) TO-263 (MP-25ZJ)

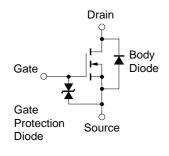


4) TO-220SMD(MP-25Z)^{Note}



Note This Package is produced only in Japan.

EQUIVALENT CIRCUIT



Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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